

N-Channel Enhancement Mode Power MOSFET

Description

The HM10N15D uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

V_{DS} = 150V,I_D =10A

 $R_{DS(ON)}$ <75m Ω @ V_{GS} =10V (Typ:62m Ω)

 $R_{DS(ON)}\,{<}80m\Omega\;\textcircled{0}\;V_{GS}{=}4.5V\quad (Typ:68m\Omega)$

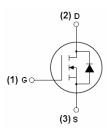
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

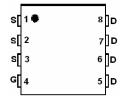
- Boost converters
- LED backlighting
- Uninterruptible power supply

100% UIS TESTED!

100% AVds TESTED!



Schematic diagram



Marking and pin assignment

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM10N15D	HM10N15D	DFN5X6-8L	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Symbol	Parameter	Limit	Unit
V _{DS}	Drain-Source Voltage	150	V
V _G s	Gate-Source Voltage	±20	V
I _D	Drain Current-Continuous	10	А
I _D (100℃)	Drain Current-Continuous(TC=100°C)	7	Α
I _{DM}	Pulsed Drain Current	30	Α
P _D	Maximum Power Dissipation	90	W
	Derating factor	0.6	W/℃
E _{AS}	Single pulse avalanche energy (Note 5)	80	mJ
T_{J}, T_{STG}	Operating Junction and Storage Temperature Range	-55 To 175	$^{\circ}$ C

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Thermal Characteristic

R _{eJC}	Thermal Resistance, Junction-to-Case (Note 2)	1.7	°C/W
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Electrical Characteristics (T_C=25°C unless otherwise noted)

	Symbol Parameter	Parameter Condition		Тур	Max	Unit
Off Characteri	stics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V I _D =250μA	150	165	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =150V,V _{GS} =0V	-	-	1	μΑ
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteri	stics (Note 3)					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =250μA 1.2		1.6	2.5	V
D	Drain Course On State Besistance	V _{GS} =10V, I _D =10A -		62	75	mΩ
$R_{DS(ON)}$	Drain-Source On-State Resistance	V _{GS} =4.5V, I _D =10A -		68	80	mΩ
9 FS	Forward Transconductance	V _{DS} =5V,I _D =10A	-	20	-	S
Dynamic Char	acteristics (Note4)		•			
C _{lss}	Input Capacitance	75/// 0//	-	2500	-	PF
C _{oss}	Output Capacitance	V_{DS} =75V, V_{GS} =0V, F=1.0MHz	-	68	-	PF
C _{rss}	Reverse Transfer Capacitance	F=1.UIVIHZ	-	54	-	PF
Switching Cha	rracteristics (Note 4)		•			
t _{d(on)}	Turn-on Delay Time		-	18.5	-	nS
t _r	Turn-on Rise Time	V_{DD} =75 V , R_L =5 Ω	-	10	-	nS
t _{d(off)}	Turn-Off Delay Time	V_{GS} =10V, R_{GEN} =3 Ω	-	22	-	nS
t _f	Turn-Off Fall Time		-	8	-	nS
Qg	Total Gate Charge	\/ 75\/ L 40A	-	60	-	nC
Q _{gs}	Gate-Source Charge	V_{DS} =75V, I_{D} =10A, V_{GS} =10V	-	7.1	-	nC
Q_{gd}	Gate-Drain Charge	V _{GS} =10V	-	17	-	nC
Drain-Source	Diode Characteristics		•			
V _{SD}	Diode Forward Voltage (Note 3)	V _{GS} =0V,I _S =10A	-	-	1.2	V
Is	Diode Forward Current (Note 2)	-	-		10	Α
t _{rr}	Reverse Recovery Time	TJ = 25°C, IF = 10A	-	34	-	nS
Qrr	Reverse Recovery Charge	di/dt = 100A/µs ^(Note3)	-	55	-	nC
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD				

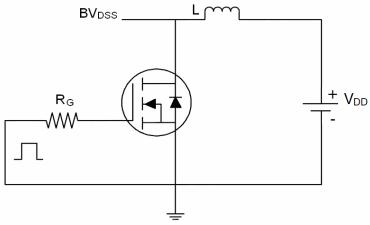
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition:Tj=25 $^{\circ}\text{C}$,V $_{DD}$ =50V,V $_{G}$ =10V,L=0.5mH,Rg=25 Ω

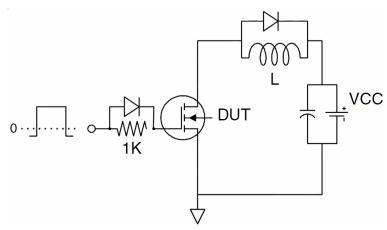


Test Circuit

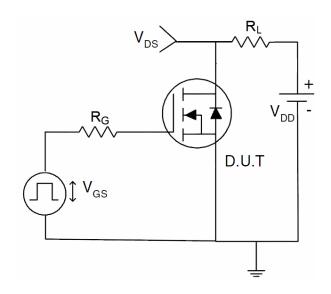
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

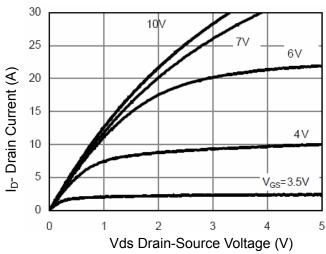


Figure 1 Output Characteristics

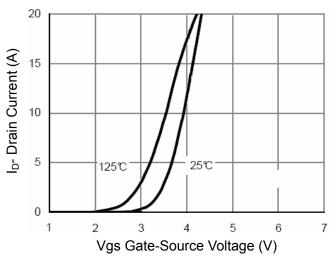


Figure 2 Transfer Characteristics

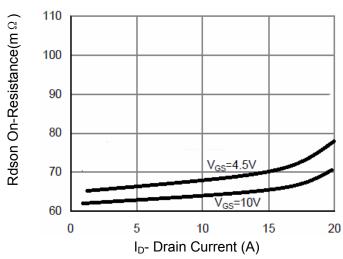


Figure 3 Rdson- Drain Current

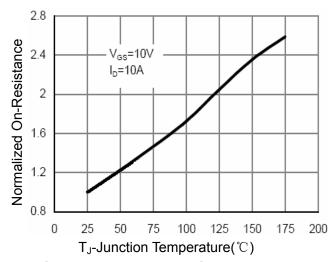


Figure 4 Rdson-JunctionTemperature

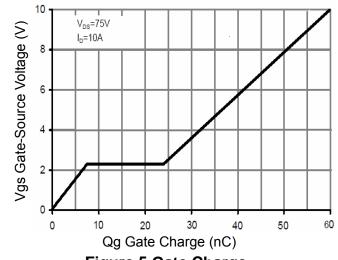


Figure 5 Gate Charge

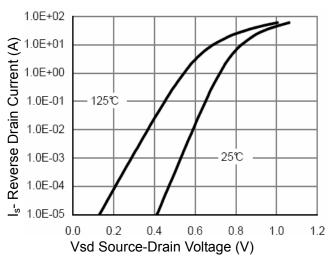
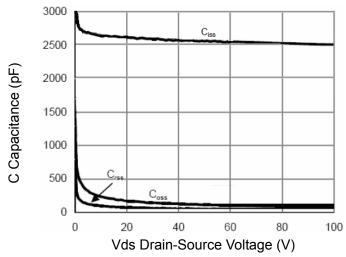


Figure 6 Source- Drain Diode Forward





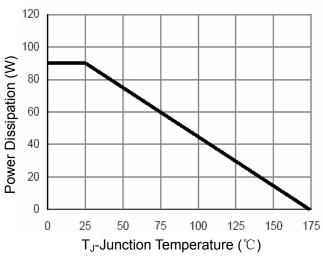
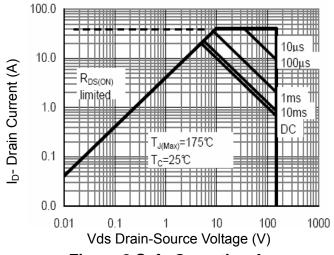


Figure 7 Capacitance vs Vds

Figure 9 Power De-rating



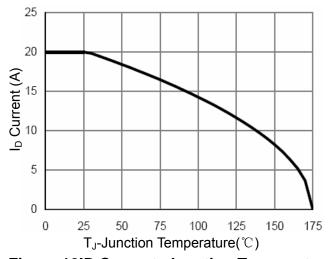
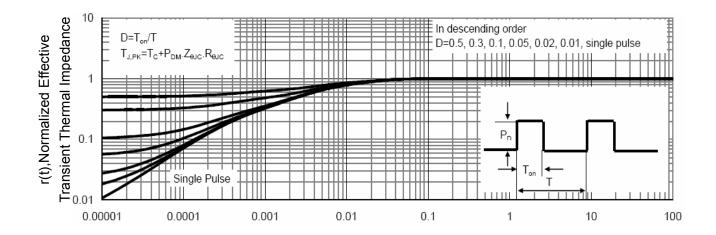


Figure 8 Safe Operation Area

Figure 10ID Current- Junction Temperature

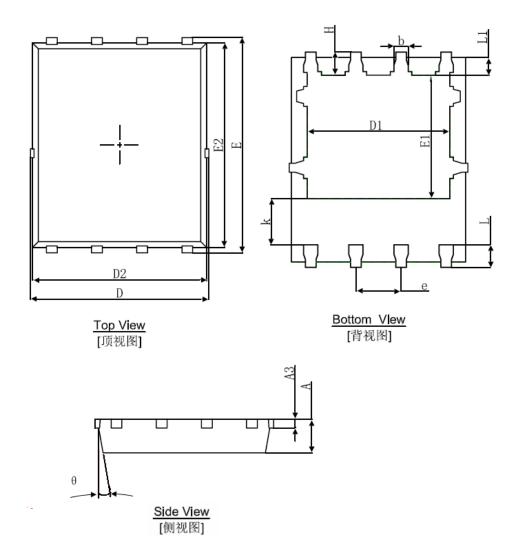


Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance



DFN5X6-8L Package Information



C) male al	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	0.900	1.000	0.035	0.039	
A3	0.254	REF.	0.010REF.		
D	4.944	5.096	0.195	0.201	
E	5.974	6.126	0.235	0.241	
D1	3.910	4.110	0.154	0.162	
E1	3.375	3.575	0.133	0.141	
D2	4.824	4.976	0.190	0.196	
E2	5.674	5.826	0.223	0.229	
k	1.190	1.390	0.047	0.055	
b	0.350	0.450	0.014	0.018	
е	1.270TYP.		0.050TYP.		
L	0.559	0.711	0.022	0.028	
L1	0.424	0.576	0.017	0.023	
Н	0.574	0.726	0.023	0.029	
θ	8°	12°	8°	12°	

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HM10N15D



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